

Application/Control No.	Applicant(s)/Patent und Reexamination	der
10/537,234	KIM ET AL.	
Examiner	Art Unit	
Michael Bernshteyn	1713	

SEARCHED				
Class	Subclass	Date	Examiner	
525	166	6/7/2006	МВ	
429	231.95	6/7/2006	МВ	
429	217	6/7/2006	MB	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPAT, JPO, EPO,DERWENT, PREGRANT)	6/7/2006	МВ
PALM, eDAN Inventors and Assignee search update	6/7/2006	МВ
NPL	6/7/2006	МВ